Amendments to the Claims:

Please cancel claim 59 and amend claim 54 as follows:

Listing of Claims:

1-53. (Cancelled)

54. (Currently Amended) A method for removing material from a microelectronic substrate, comprising:

engaging the microelectronic substrate with a planarizing medium;

moving at least one of a first part of the microelectronic substrate and a first portion of the planarizing medium relative to the other at a first rate;

moving at least one of a second part of the microelectronic substrate and the <u>first</u> portion of the planarizing medium relative to the other at a second rate less than the first rate;

advancing the polishing medium from a supply roller to a take up roller to engage a second portion of the polishing medium with the first and second parts of the microelectronic substrate; and

removing material from the first and second parts of the microelectronic substrate at approximately equal rates by biasing the first part of the microelectronic substrate against the planarizing medium with a first membrane portion having a first thickness and biasing the second part of the microelectronic substrate against the planarizing medium with a second membrane portion having a second thickness greater than the first thickness.

- 55. (Original) The method of claim 54 wherein engaging the microelectronic substrate with the planarizing medium includes engaging the microelectronic substrate with a polishing pad.
- 56. (Original) The method of claim 54 wherein moving at least one of the first part of the microelectronic substrate and the planarizing medium includes moving at 1 ast

PAGE 5/8 * RCVD AT 4/7/2004 1:19:50 PM [Eastern Daylight Time] * SVR:USPTO-EFXRF-115 * DNIS:8729306 * CSID:206 903 8820 * DURATION (mm-ss):02-30

Appl No. 09/910,638

one of a first annular part of the microelectronic substrate and the planarizing medium, further wherein moving at least one of the second part of the microelectronic substrate and the planarizing medium includes moving at least one of the planarizing medium and a second annular part of the microelectronic substrate positioned radially inwardly from the first annular part of the microelectronic substrate.

57. (Cancelled)

58. (Original) The method of claim 54 wherein the membrane has a first surface facing toward the microelectronic substrate and a second surface facing generally opposite the first surface, further wherein biasing the microelectronic substrate against the planarizing medium includes biasing a generally flat support member against the second surface of the membrane.

59. (Cancelled)